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AMENDMENTS TO THE CLAIMS:

This listing of claims will replace all prior versions, and listings, of claims in the application:

LISTING OF CLAIMS:

Claim 1 (currently amended): A method for selecting a piezoelectric transformer having a desired characteristic which is performed in a method of manufacturing a piezoelectric transformer, comprising the steps of:

connecting a primary-side driving section of a piezoelectric transformer to a high-frequency generator while leaving a secondary-side generating section thereof in an open state;

causing said high-frequency generator to sequentially generate and sweep a high-frequency signal over a predetermined frequency range;

measuring a resonant frequency of an input-impedance-versus-frequency characteristic of the piezoelectric transformer;

selecting the piezoelectric transformer if said piezoelectric transformer has a desired characteristic based on the value of the measured resonant frequency; and

rejecting the piezoelectric transformer if the piezoelectric transformer does not have a desired characteristic based on the value of the measured resonant frequency;

and

completing the manufacturing of the piezoelectric transformer after the steps of selecting and rejecting.

Claim 2 (original): The method according to claim 1, wherein the step of measuring the piezoelectric transformer is done while the piezoelectric transformer is in an isolated state in which the piezoelectric transformer is not mounted on a mounting

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substrate.

Claim 3 (original): The method according to claim 1, wherein only the input-impedance-versus-frequency characteristic of the piezoelectric transformer is measured.

Claim 4 (currently amended): A method for selecting a piezoelectric transformer having a desired characteristic which is performed in a method of manufacturing a piezoelectric transformer, comprising the steps of:

connecting a primary-side driving section of a piezoelectric transformer to a high-frequency generator while leaving a secondary-side generating section thereof in an open state;

causing said high-frequency generator to sequentially generate and sweep a high-frequency signal over a predetermined frequency range;

measuring a bandwidth of an input-impedance-versus-frequency characteristic of the piezoelectric transformer by subtracting a resonant-frequency f_r from an antiresonant-frequency f_a ;

selecting the piezoelectric transformer if the piezoelectric transformer has a desired characteristic based on the value of the measured bandwidth; and

rejecting the piezoelectric transformer if the piezoelectric transformer does not have a desired characteristic based on the value of the measured bandwidth; and

completing the manufacturing of the piezoelectric transformer after the steps of selecting and rejecting.

Claim 5 (original): The method according to claim 4, wherein the step of measuring the piezoelectric transformer is done while the piezoelectric transformer is in an isolated state in which the piezoelectric transformer is not mounted on a mounting

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substrate.

Claim 6 (original): The method according to claim 4, wherein only the input-impedance-versus-frequency characteristic of the piezoelectric transformer is measured.

Claim 7 (currently amended): A method for selecting a piezoelectric transformer having a desired characteristic which is performed in a method of manufacturing a piezoelectric transformer, comprising the steps of:

connecting a primary-side driving section of a piezoelectric transformer to a high-frequency generator while leaving a secondary-side generating section thereof in an open state;

causing said high-frequency generator to sequentially generate and sweep a high-frequency signal over a predetermined frequency range;

measuring a resonant resistance from an input-impedance-versus-frequency characteristic of the piezoelectric transformer;

selecting the piezoelectric transformer if the piezoelectric transformer has a desired characteristic based on the value of the measured resonant resistance; and

rejecting the piezoelectric transformer if the piezoelectric transformer does not have a desired characteristic based on the value of the measured resonant resistance;
and

completing the manufacturing of the piezoelectric transformer after the steps of selecting and rejecting.

Claim 8 (original): The method according to claim 7, wherein the step of measuring the piezoelectric transformer is done while the piezoelectric transformer is in an isolated state in which the piezoelectric transformer is not mounted on a mounting

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substrate.

Claim 9 (original): The method according to claim 7, wherein only the input-impedance-versus-frequency characteristic of the piezoelectric transformer is measured.

Claim 10 (currently amended): A method for selecting a piezoelectric transformer having a desired characteristic which is performed in a method of manufacturing a piezoelectric transformer, comprising the steps of:

connecting a primary-side driving section of a piezoelectric transformer to a high-frequency generator while leaving a secondary-side generating section thereof in an open state;

causing said high-frequency generator to sequentially generate and sweep a high-frequency signal over a predetermined frequency range;

measuring a resonant frequency, a bandwidth, and a resonant resistance from an input-impedance-versus-frequency characteristic of the piezoelectric transformer in which the bandwidth is determined by subtracting a resonant-frequency f_r from an antiresonant-frequency f_a ;

selecting the piezoelectric transformer if the piezoelectric transformer has a desired characteristic based on the values of the measured resonant frequency, the bandwidth, and the resonant resistance; and

rejecting the piezoelectric transformer if the piezoelectric transformer does not have a desired characteristic based on the values of the measured resonant frequency, the bandwidth, and the resonant resistance; and

completing the manufacturing of the piezoelectric transformer after the steps of selecting and rejecting.

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Claim 11 (original): The method according to claim 10, wherein the step of measuring the piezoelectric transformer is done while the piezoelectric transformer is in an isolated state in which the piezoelectric transformer is not mounted on a mounting substrate.

Claim 12 (original): The method according to claim 10, wherein only the input-impedance-versus-frequency characteristic of the piezoelectric transformer is measured.

Claim 13 (currently amended): A method for selecting a piezoelectric transformer having a desired characteristic which is performed in a method of manufacturing a piezoelectric transformer, comprising the steps of:

connecting a primary-side driving section of a piezoelectric transformer to a high-frequency generator while leaving a secondary-side generating section thereof short-circuited;

causing said high-frequency generator to sequentially generate and sweep a high-frequency signal over a predetermined frequency range;

measuring a resonant frequency of an input-impedance-versus-frequency characteristic of the piezoelectric transformer;

selecting the piezoelectric transformer if the piezoelectric transformer has a desired characteristic based on the value of the measured resonant frequency; and

rejecting the piezoelectric transformer if the piezoelectric transformer does not have a desired characteristic based on the value of the measured resonant frequency;

and

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Claim 14 (original): The method according to claim 13, wherein the step of measuring the piezoelectric transformer is done while the piezoelectric transformer is in an isolated state in which the piezoelectric transformer is not mounted on a mounting substrate.

Claim 15 (original): The method according to claim 13, wherein only the input-impedance-versus-frequency characteristic of the piezoelectric transformer is measured.

Claim 16 (currently amended): A method for selecting a piezoelectric transformer having a desired characteristic which is performed in a method of manufacturing a piezoelectric transformer, comprising the steps of:

connecting a primary-side driving section of a piezoelectric transformer to a high-frequency generator while leaving a secondary-side generating section thereof short-circuited;

causing said high-frequency generator to sequentially generate and sweep a high-frequency signal over a predetermined frequency range;

measuring a bandwidth of an input-impedance-versus-frequency characteristic of the piezoelectric transformer by subtracting a resonant-frequency from an antiresonant-frequency;

selecting the piezoelectric transformer if the piezoelectric transformer has a desired characteristic based on the value of the measured bandwidth; and

rejecting the piezoelectric transformer if the piezoelectric transformer does not have a desired characteristic based on the value of the measured bandwidth; and

completing the manufacturing of the piezoelectric transformer after the steps of selecting and rejecting.

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Claim 17 (original): The method according to claim 16, wherein the step of measuring the piezoelectric transformer is done while the piezoelectric transformer is in an isolated state in which the piezoelectric transformer is not mounted on a mounting substrate.

Claim 18 (original): The method according to claim 16, wherein only the input-impedance-versus-frequency characteristic of the piezoelectric transformer is measured.

Claim 19 (currently amended): A method for selecting a piezoelectric transformer having a desired characteristic which is performed in a method of manufacturing a piezoelectric transformer, comprising the steps of:

connecting a primary-side driving section of a piezoelectric transformer to a high-frequency generator while leaving a secondary-side generating section thereof short-circuited;

causing said high-frequency generator to sequentially generate and sweep a high-frequency signal over a predetermined frequency range;

measuring a resonant resistance of an input-impedance-versus-frequency-characteristic of the piezoelectric transformer;

selecting the piezoelectric transformer if the piezoelectric transformer has a desired characteristic based on the value of the measured resonant resistance; and

rejecting the piezoelectric transformer if the piezoelectric transformer does not have a desired characteristic based on the value of the measured resonant resistance;

and

completing the manufacturing of the piezoelectric transformer after the steps of selecting and rejecting.

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Claim 20 (original): The method according to claim 19, wherein the step of measuring the piezoelectric transformer is done while the piezoelectric transformer is in an isolated state in which the piezoelectric transformer is not mounted on a mounting substrate.

Claim 21 (original): The method according to claim 19, wherein only the input-impedance-versus-frequency characteristic of the piezoelectric transformer is measured.

Claim 22 (currently amended): A method for selecting a piezoelectric transformer having a desired characteristic which is performed in a method of manufacturing a piezoelectric transformer, comprising the steps of:

connecting a primary-side driving section of a piezoelectric transformer to a high-frequency generator while leaving a secondary-side generating section thereof short-circuited;

causing said high-frequency generator to sequentially generate and sweep a high-frequency signal over a predetermined frequency range;

measuring a resonant frequency, a bandwidth, and a resonant resistance of an input-impedance-versus-frequency characteristic of the piezoelectric transformer in which the bandwidth is determined by subtracting a resonant-frequency from an antiresonant-frequency;

selecting the piezoelectric transformer if the piezoelectric transformer has a desired characteristic based on the values of the measured resonant frequency, the bandwidth, and the resonant resistance; and

rejecting the piezoelectric transformer if the piezoelectric transformer does not have a desired characteristic based on the measured resonant frequency, the bandwidth, and the resonant resistance; and

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completing the manufacturing of the piezoelectric transformer after the steps of selecting and rejecting.

Claim 23 (original): The method according to claim 22, wherein the step of measuring the piezoelectric transformer is done while the piezoelectric transformer is in an isolated state in which the piezoelectric transformer is not mounted on a mounting substrate.

Claim 24 (original): The method according to claim 22, wherein only the input-impedance-versus-frequency characteristic of the piezoelectric transformer is measured.